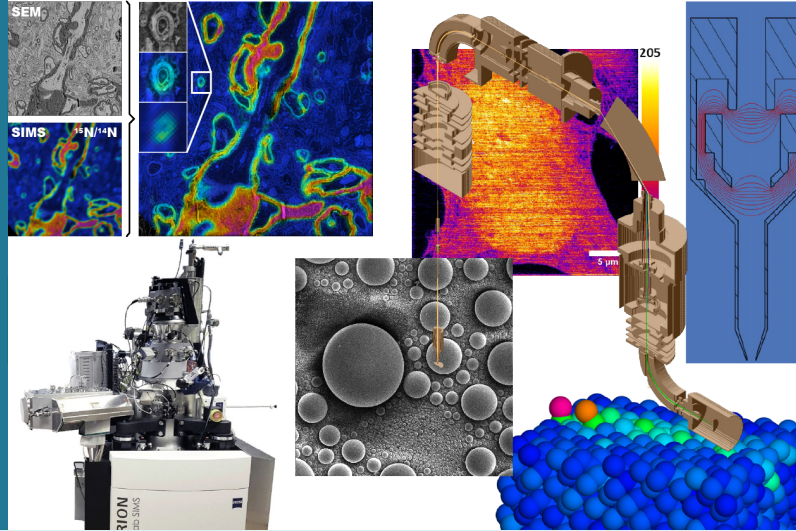


Advanced Instrumentation for Nano-Analytics



The 'Advanced Instrumentation for Nano-Analytics' (AINA) group focuses on the development of scientific instruments based on charged particle beams and laser beams and correlative workflows taking advantage of these instruments. The group's R&D activity covers fundamental investigations, instrument development and application development. The targeted fields of application of the instrumentation and methodologies developed by AINA are:

- nano-imaging
- nano-analysis
- in-situ process control for nano-fabrication
- neutral gas, plasma & liquid flow diagnostics



Our research activities are performed in cooperation with leading international instrument manufacturers and with research groups specialized in the relevant fields.

Main expertise fields

- [Nano-analytics](#)
- [Charged particle optics](#)
- [Laser optics](#)
- [Vacuum and laser ion injection](#)
- [Instrument development and prototyping \(including mechanics, electronics, software development\)](#)

Research challenges

The development of innovative characterization tools is of paramount importance to advance the frontiers of materials science. Due to the ever-increasing complexity of devices and continuously shrinking geometries in materials science and engineering, the characterization tools and techniques are facing new challenges and need to anticipate future trends:

- The development of new hardware to improve following aspects of nano-analytics:
 - Lateral resolution
 - Sensitivity
 - Throughput
 - Automation
- The development of correlative workflows to maximize information by combining results from different, complementary techniques
- The development of new algorithms and software to deal with the increasing complexity of data and to prepare for automation of data treatment
- The aforementioned developments need to be applicable to the fields of:
 - materials science
 - life science
 - and beyond

Application areas

- [Instruments for correlative microscopy](#)
- [Instrumentation for nano-analytics](#)
- [Correlative microscopy and applications in materials science and life sciences](#)
- [In-situ treatment and passivation for correlative microscopy](#)
- [Particle matter characterisation for ion microscopy](#)

Main assets

- Experienced and multidisciplinary team
- Expertise covering the full spectrum required to turn innovative concepts and ideas into prototype instruments
- Long-term collaborations with world-leading instrument manufacturers
- Strong patent portfolio in the fields of focus



Equipment

- 2 Zeiss ORION NanoFab HM equipped with in-house developed SIMS, STM, etc.
- 1 Thermo Fisher Scico Dualbeam equipped with in-house developed SIMS
- 1 Thermo Fisher Techna F20 TEM equipped with in-house developed SIMS
- 1 Prototype IBC for field-portable and space applications
- 1 SIMS for fundamental studies and component testing (CMS)
- 1 In-house build He-STM microscope for ion transmission studies (Galileo)
- 1 Test benches for charged particle optics instrumentation
- 1 specialised glove box for cryo preparation and sample transfer purposes
- 1 prototype coherent X-ray Bragg scattering laser (2.3 J/pulse, 100fs chirp rate)
- 1 Continuum Powerlite (1.8J @ 2064 nm, 1.1J @ 523nm)
- 1 Scan Precision scan (200-900nm)
- 1 Topica Femtoforce ultra 2050

Review papers and book chapters

- Audinet, J.-R.; Philipp, P.; Du Castro, O.; Bissemvier, A.; Hoang, Q. H.; Wirtz, T. Highest resolution chemical imaging based on secondary ion mass spectrometry performed on the helium ion microscope. *Rep. Prog. Phys.* 2021, 84, 059001. DOI: 10.1088/1361-6633/acc130
- Wirtz, T.; Du Castro, O.; Audinet, J.-R.; Philipp, P. Imaging and Analytics on the Helium Ion Microscope. *Annu. Rev. Anal. Chem.* 2019, 12 (1), 523-543. DOI: 10.1146/annurev-anchem-061318-115457
- Ewars, S.; Polanski, A.; Yelka, L.; Heide, Q. H.; Lohvic, J.; Philipp, P.; Wirtz, T. Correlative Microscopy Combining Transmission Electron Microscopy and Secondary Ion Mass Spectrometry: A General Review on the State-of-the-Art, Recent Developments, and Prospects. *Appl. Phys. Rev.* 2019, 6 (2), 021312. DOI: 10.1063/1.5064758
- Ewars, S.; Polanski, A.; Philipp, P. SIMS on the Helium Ion Microscope: A Powerful Tool for High-Resolution High-Sensitivity Nano-Analytics. In *Helium Ion Microscopy*; Hawakel, G., Gilzbauer, A., Eds.; Springer International Publishing Switzerland, 2016. DOI: 10.1007/978-3-319-41969-9_13. DOI: 10.1007/978-3-319-41969-9_13
- Wirtz, T.; Philipp, P.; Audinet, J.-R.; Chevallier, D.; Ewars, S. High-Resolution High-Sensitivity Elemental Imaging by Secondary Ion Mass Spectrometry: From Traditional 2D and 3D Imaging to Correlative Microscopy. *Nanotechnology* 2015, 26 (43), 434001. DOI: 10.1088/0957-4484/26/43/434001

Partners

inspace Europe, Luxembourg, Photonis, The Netherlands, RAITH, Surface Concept, Germany, Thermo Fisher, The Netherlands, Zeiss, Germany, Zeiss PCS, USA, zeroK, US

Contact

5, avenue des Hauts-Fourneaux
L-4362 Esch-sur-Alzette
phone: +352 275 888 - 1 | LIST.lu

Dr Tom WIRTZ (tom.wirtz@list.lu)
© Copyright February 2025 LIST

LUXEMBOURG
INSTITUTE OF SCIENCE
AND TECHNOLOGY

